

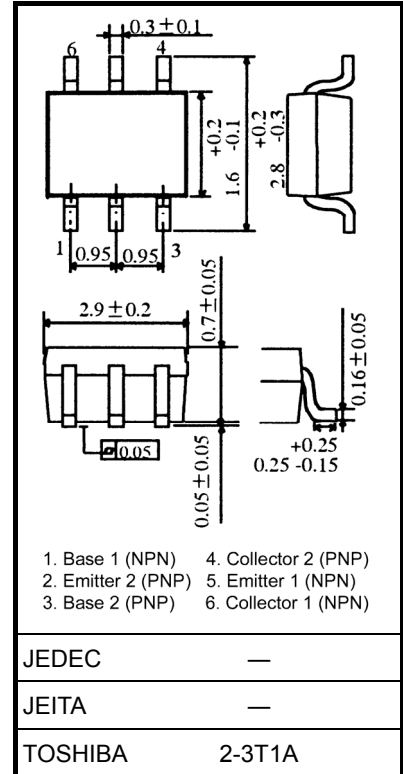
TOSHIBA Multi-Chip Transistor Silicon NPN & PNP Epitaxial Type

TPC6901

High-Speed Switching Applications
 MOS Gate Drive Applications

- NPN and PNP transistors are mounted on a compact and slim package.
- High DC current gain: NPN $h_{FE} = 400$ to 1000
 : PNP $h_{FE} = 200$ to 500
- Low collector-emitter saturation voltage
 : NPN $V_{CE(sat)} = 0.17$ V (max)
 : PNP $V_{CE(sat)} = 0.23$ V (max)
- High-speed switching: NPN $t_f = 85$ ns (typ.)
 : PNP $t_f = 70$ ns (typ.)

Unit: mm



Weight: 0.011 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating		Unit	
		NPN	PNP		
Collector-base voltage	V _{CBO}	100	-50	V	
Collector-emitter voltage	V _{CEX}	80	-50	V	
Collector-emitter voltage	V _{CEO}	50	-50	V	
Emitter-base voltage	V _{EBO}	7	-7	V	
Collector current	DC (Note 1)	I _C	1.0	0.7	A
	Pulse (Note 1)	I _{CP}	2.0	-2.0	A
Base current	I _B	0.1	-0.1	A	
Collector power dissipation (t=10 s) (Note 2)	Single-device operation P _{C(1)}	500		mW	
Collector power dissipation (DC) (Note 2)	Single-device operation P _{C(2)}	400		mW	
	Single-device value at dual operation P _{C(3)}	330			
Thermal resistance, junction to ambient (t=10 s) (Note 2)	Single-device operation R _{th(j-a)} (1)	250		°C/W	
Thermal resistance, junction to ambient (DC) (Note 2)	Single-device operation R _{th(j-a)} (2)	312		°C/W	
	Single-device value at dual operation R _{th(j-a)} (3)	378			
Junction temperature	T _j	150		°C	
Storage temperature range	T _{stg}	-55 to 150		°C	

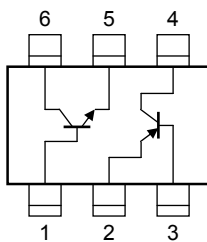
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm²)

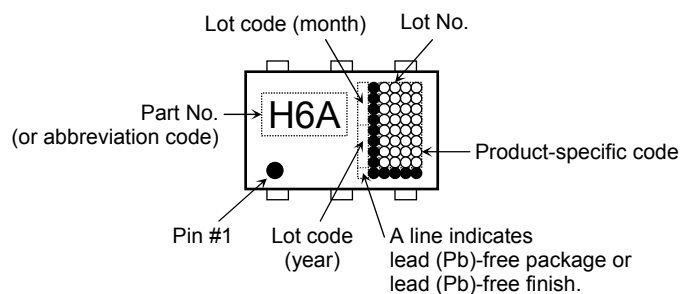
Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Circuit Configuration



Marking



Electrical Characteristics (Ta = 25°C) : NPN

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		I_{CBO}	$V_{CB} = 100\text{ V}, I_E = 0$	—	—	100	nA
Emitter cut-off current		I_{EBO}	$V_{EB} = 7\text{ V}, I_C = 0$	—	—	100	nA
Collector-emitter breakdown voltage		$V_{(BR)CEO}$	$I_C = 10\text{ mA}, I_B = 0$	50	—	—	V
DC current gain		$h_{FE} (1)$	$V_{CE} = 2\text{ V}, I_C = 0.1\text{ A}$	400	—	1000	
		$h_{FE} (2)$	$V_{CE} = 2\text{ V}, I_C = 0.3\text{ A}$	200	—	—	
Collector-emitter saturation voltage		$V_{CE(sat)}$	$I_C = 300\text{ mA}, I_B = 6\text{ mA}$	—	—	0.17	V
Base-emitter saturation voltage		$V_{BE(sat)}$	$I_C = 300\text{ mA}, I_B = 6\text{ mA}$	—	—	1.10	V
Collector output capacitance		C_{ob}	$V_{CB} = 10\text{ V}, I_E = 0, f = 1\text{ MHz}$	—	5	—	pF
Switching time	Rise time	t_r	See Figure 1 circuit diagram. $V_{CC} \approx 30\text{ V}, R_L = 100\ \Omega$ $I_{B1} = -I_{B2} = 10\text{ mA}$	—	35	—	ns
	Storage time	t_{stg}		—	680	—	
	Fall time	t_f		—	85	—	

Electrical Characteristics (Ta = 25°C) : PNP

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		I_{CBO}	$V_{CB} = -50\text{ V}, I_E = 0$	—	—	-100	nA
Emitter cut-off current		I_{EBO}	$V_{EB} = -7\text{ V}, I_C = 0$	—	—	-100	nA
Collector-emitter breakdown voltage		$V_{(BR)CEO}$	$I_C = -10\text{ mA}, I_B = 0$	-50	—	—	V
DC current gain		$h_{FE} (1)$	$V_{CE} = -2\text{ V}, I_C = -0.1\text{ A}$	200	—	500	
		$h_{FE} (2)$	$V_{CE} = -2\text{ V}, I_C = -0.3\text{ A}$	125	—	—	
Collector-emitter saturation voltage		$V_{CE(sat)}$	$I_C = -300\text{ mA}, I_B = -10\text{ mA}$	—	—	0.23	V
Base-emitter saturation voltage		$V_{BE(sat)}$	$I_C = -300\text{ mA}, I_B = -10\text{ mA}$	—	—	1.10	V
Collector output capacitance		C_{ob}	$V_{CB} = -10\text{ V}, I_E = 0, f = 1\text{ MHz}$	—	8	—	pF
Switching time	Rise time	t_r	See Figure 2 circuit diagram. $V_{CC} \approx 30\text{ V}, R_L = 100\ \Omega$ $I_{B1} = -I_{B2} = -10\text{ mA}$	—	60	—	ns
	Storage time	t_{stg}		—	280	—	
	Fall time	t_f		—	70	—	

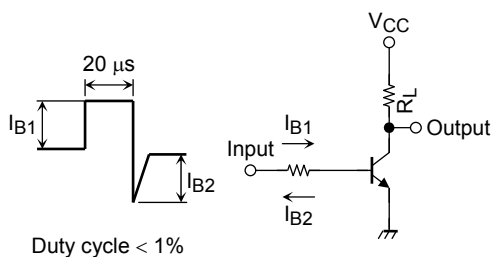


Figure 1 Switching Time Test Circuit & Timing Chart (NPN)

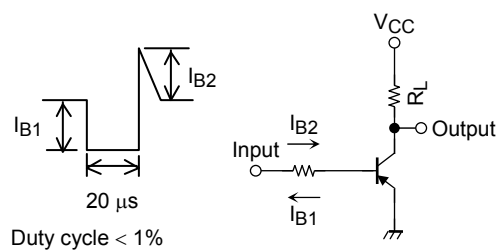
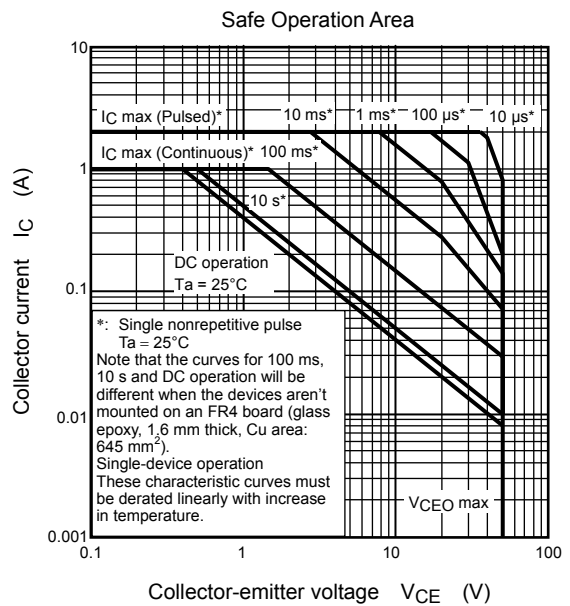
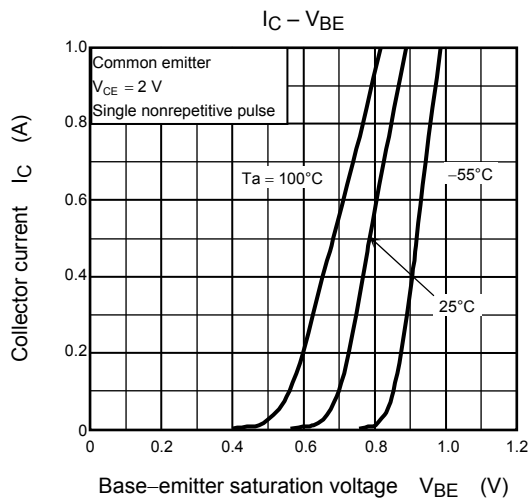
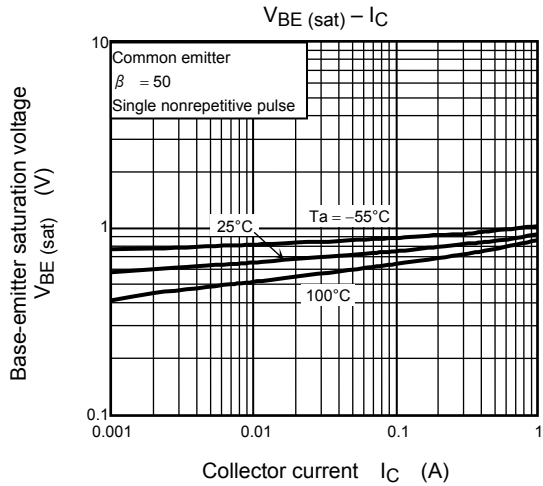
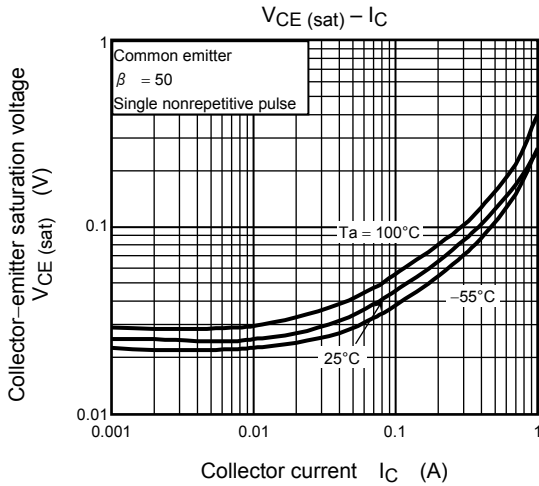
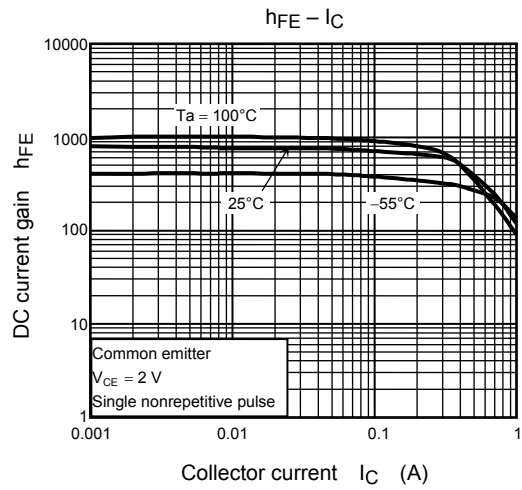
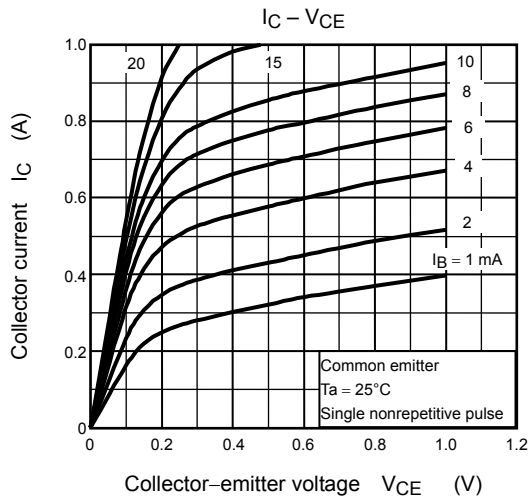
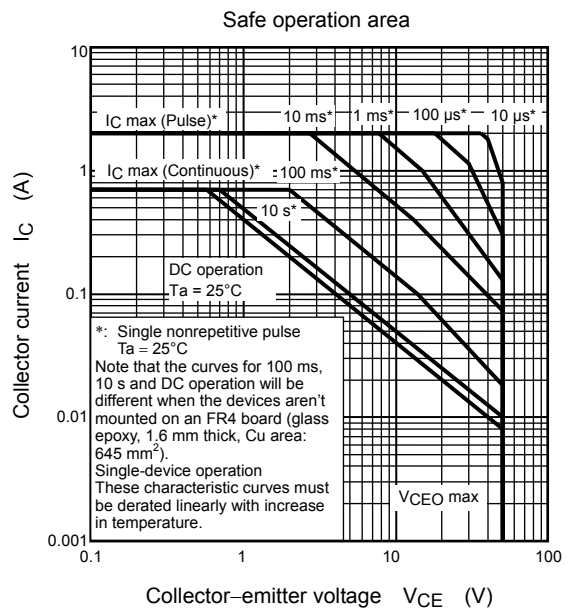
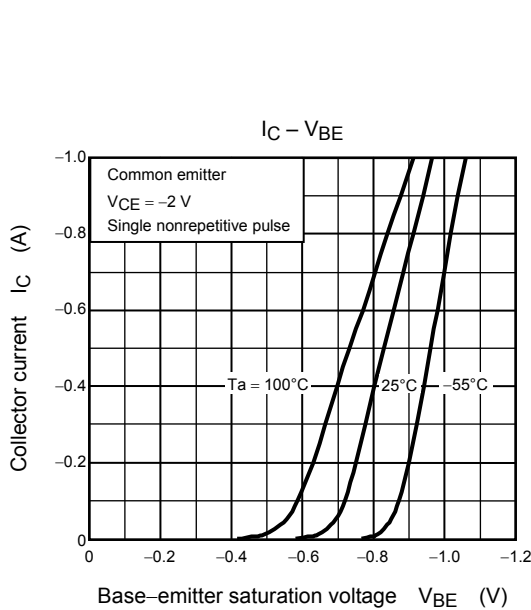
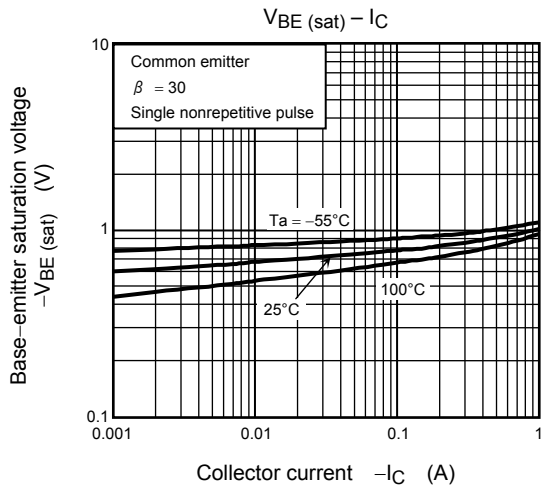
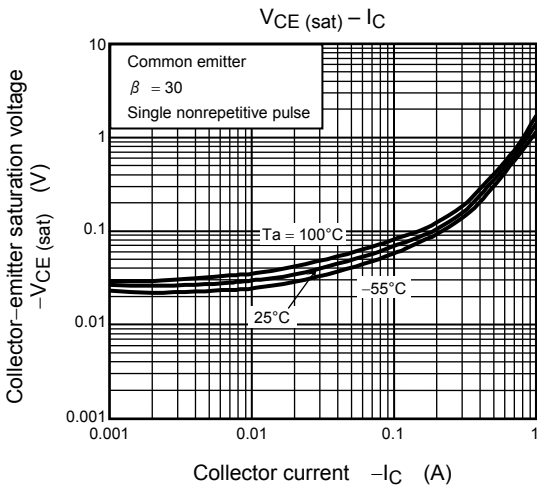
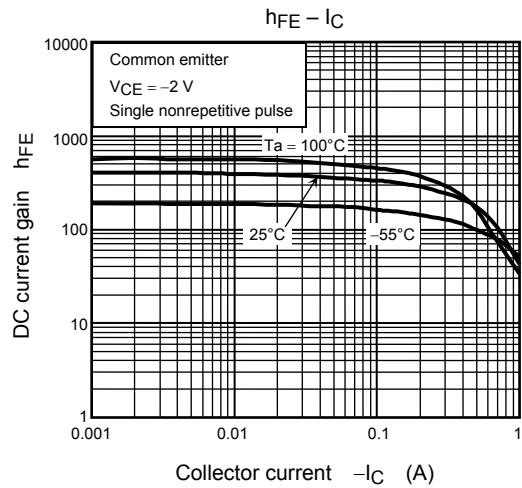
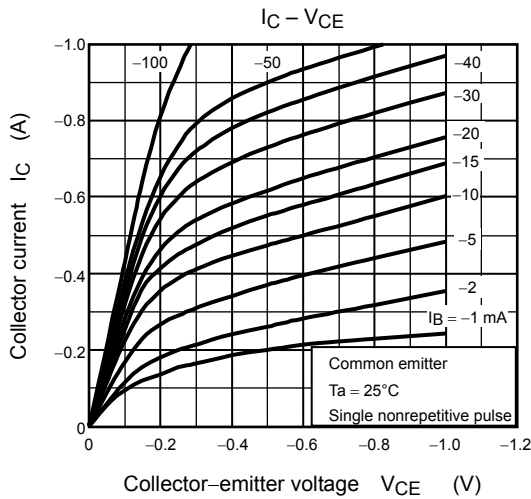


Figure 2 Switching Time Test Circuit & Timing Chart (PNP)

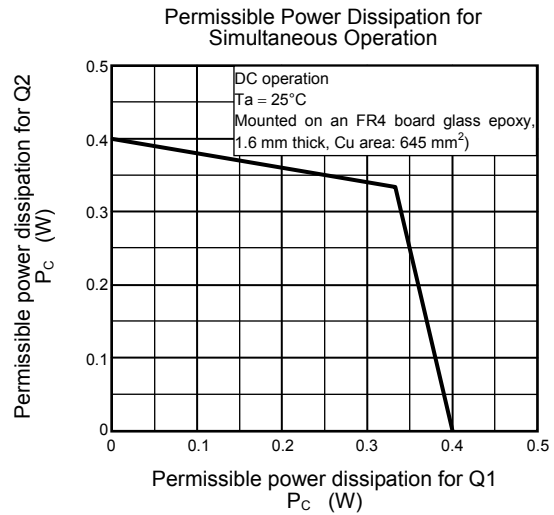
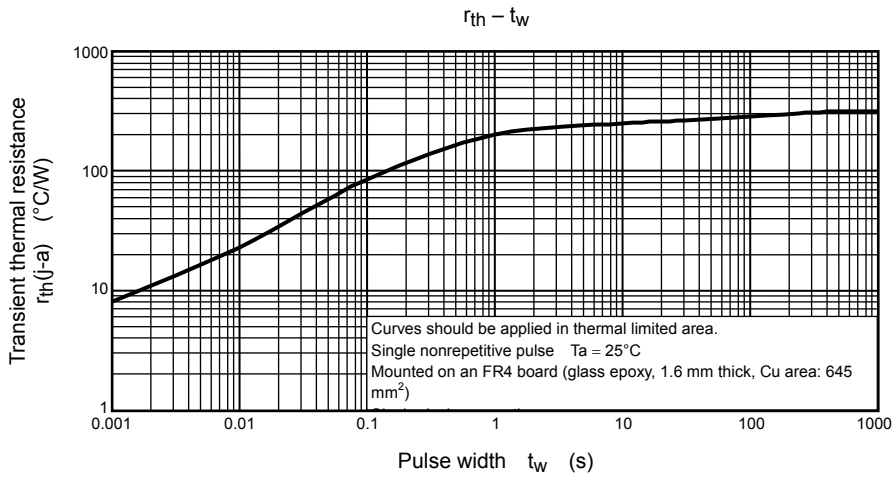
NPN



PNP



Common



Collector power dissipation at the single-device operation is 0.4W.
 Collector power dissipation at the single-device value at dual operation is 0.33W.
 Collector power dissipation at the dual operation is set to 0.66W.

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20070701-EN

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